Search Notes



App	licat	ion/	Contr	1 lo	10
-----	-------	------	-------	------	----

10549752

Examiner

Faulk, Devona E

Applicant(s)/Patent Under Reexamination

YANO, ATSUYOSHI

Art Unit

2615

SEARCHED

Class	Subclass	Date	Examiner
391	98-101	2/6/2008	DEF
704	233,267,211,278,500,501,211	2/18/2008	DEF

SEARCH NOTES

Search Notes	Date	Examiner
Assignee/Inventor search	2/6/2008	DEF
word search; combined class/word search	2/6,8,13,14,18/0	DEF
	8	

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

·U.S. Patent and Trademark Office

Part of Paper No.: 20080208